

Search Notes

Application/Control No.

10/584,134

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

YOSHIDA, NAOHIRO

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	65.3 65.4 65.2 65.8	11/2/2007	HP
	65.6		
429	17	11/2/2007	HP
	19		
701	22	11/2/2007	HP
318	727	11/2/2007	HP
	700		
320	104	11/2/2007	HP
	126		
	101		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search	11/2/2007	HP